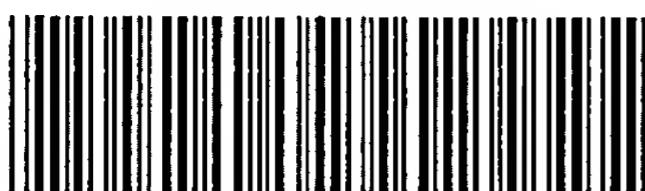


Search Notes



Application/Control No.

10/621.417

Examiner

Hai C. Pham

**Applicant(s)/Patent under
Reexamination**

MOTOYAMA, HAJIME

Art Unit

2861

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

INTERFERENCE SEARCHED

INTERFERENCE SEARCHED